ZEISS scatterControl Exceptional CT image quality



The hardware solution for optimized image quality

ZEISS scatterControl significantly improves the image quality of CT scans and reduces scatter artifacts to a minimum. These improvements enable subsequent data management and evaluation steps for suitable parts, resulting in even more accurate surface determination and defect analysis.

The product is ideal for highly voluminous and dense parts, such as additively manufactured metal parts and aluminum cast parts, even with steel inlays, as well as for other assemblies containing denser materials.

The module is available for **ZEISS METROTOM 1500 225kV G3**, either as a retrofit solution or as part of the purchasing of a new system. Upgrade your system with ZEISS scatterControl now and benefit from superior image quality for much easier data evaluation.

Superior quality due to module positioning

ZEISS scatterControl is positioned between the tube and the detector. Smaller objects like dense additively manufactured parts are placed in front of the module, larger objects behind it.

The built-in physical collision sensor and the sophisticated collision prediction software effectively prevent crashes.



Applications

ZEISS scatterControl is ideal for a range of parts, especially highly voluminous and dense parts, and different industries such as:

Foundry

Massive aluminum or magnesium parts, even with steel inlays

Automotive Castings with steel inlays, power electronics

Additive manufacturing Dense, metal printed parts



Improved 3D inspection

Improvements on the volume data result in much easier evaluation. 3D surfaces are determined and rendered without distracting artifacts. Many artifacts are typically a result of scattered radiation and cause 3D pseudo surfaces that prevent accurate measurement.

Take a look at the improved quality of **2D slices** and **3D surfaces** thanks to ZEISS scatterControl.







Benefit from ZEISS scatterControl



Better image quality, better defect detection

The module significantly improves CT image quality by reducing the occurrence of artifacts caused by scattered radiation. The increased contrast simplifies defect detection considerably.



Improved surface determination

The overall quality of surface determination benefits from ZEISS scatterControl. This is a considerable advantage for metrology applications on challenging parts.



Fast scanning with VAST mode

ZEISS scatterControl works in both 'Stop and Go' and VAST scanning mode.



Easy to use

As a one-click solution, the module works seamlessly with other useful features, such as VHD, AMMAR or VoluMerge, and is fully integrated in the software.